


<b>Search Notes</b> 	<b>Application/Control No.</b> 1053086111161526	<b>Applicant(s)/Patent Under Reexamination</b> FUKUSHIMA ET AL.HSIEH, MIN-SHENG
	<b>Examiner</b> Nguyen, Lauren Nguyen, Lauren	<b>Art Unit</b> 28712871

SEARCHED			
Class	Subclass	Date	Examiner
349	15, 201-202	04/03/2007	LN
359	376, 462	04/03/2007	LN

SEARCH NOTES		
Search Notes	Date	Examiner
Consulted Primary Examiner Andrew Schechter	04/03/2007	LN

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner